CNFULL (China (CN) Patents Full Text)

Subject Coverage	All patent-relevant areas of science and technology, i.e., all classes of the International Patent Classification
File Type	Full-Text

Features

Thesauri	International Patent Classification (/IPC), Cooperative Patent Classification (CPC), European Patent Classification (/EPC)		
Alerts (SDIs)	Weekly or monthly (weekly is the default)		
CAS Registry Numbers® Identifiers	☐	SLART	☑
Keep & Share	☑	Structures	☐
Register Links	☑		

Record Content

- Full-text of patent applications, granted patents, utility models and design patents published in People's Republic of China from 1985 onwards.
- Records are available about a week after publication date with the complete content
- Records contain bibliographic data including patent assignee and inventor, patent, application, priority, and related (PCT) application data, IPC, CPC and EPC classification codes, abstract, and full text of description and claims.
- Titles and abstracts are initially machine translated and about three months later replaced by human translated text; descriptions and claims are machine translated.
- Independent claims and claim groups are searchable for all claims in English.
- Numeric values of 59 physical and chemical properties are searchable in about 20.000 variants of the base and additional units within all full text fields in English.
- Ultimate Owners are searchable in the field /UO and /UOS.
- Standardized and normalized patent assignee names are searchable in their own fields /PAS and /PAN.
- Key terms, indexed and displayed in the field /KT, enhance retrieval of relevant results, and make the evaluation of results more efficient. They are useful to broaden search scope more precisely than Basic Index searches.
- The Locarno classification (/LCL) is available for design patents.
- Database records comprise all documents published for one application.
- Clipped images (mostly front-page images) are also included, when available.
- Some of the full text has been created by Optical Character Recognition (OCR) software. Therefore, characters may be misinterpreted, or portions of the text may be incomplete.

File Size

- More than 48 million family records with more than 55 million publications (07/2024)
- More than 36 million front page images (07/2024)

Coverage	1985 – present
Updates	Weekly
Language	English
Database Producer	LexisNexis Business Information Solutions B.V. Radarweg 29 1043 NX Amsterdam The Netherlands

Sources

Patent applications, granted patents, and utilities models published by the State Intellectual Property Office in the People's Republic of China

User Aids

- Online Helps (HELP DIRECTORY lists all help messages available)
- STNGUIDE

Clusters

- AEROTECH
- ALLBIB
- AUTHORS
- CORPSOURCE
- ENGINEERING
- FULLTEXT
- HPATENTS
- NPS
- PATENTS
- PNTTEXT

STN Database Cluster information

Search and Display Field Codes

If multiple search terms are linked with an AND operator, all terms are searched in the complete database record, i.e., in all publications referring to one application. For a search in a specific publication of the record, connect the search term and the patent kind code with the (L)-proximity operator, e.g.,
S BOREHOLE/AB,TI,CLM (L) CNA/PK limits the search to Chinese applications CNA.

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TI), abstract (AB), detailed description (DETD), claims (CLM), main claims (MCLM) and Key Terms (KT) fields	None or /BI	S TRANSISTOR AND ELECTRODE S ACOUSTIC SENSOR S ?TRANSFER?	TI, AB, DETD, CLM, MCLM
Abstract*	/AB	S BOREHOLE/AB	AB
Abstract (English)*	/ABEN	S BOREHOLE/ABEN	AB, ABEN
Accession Number	/AN	S 2010006109/AN	AN
Agent Number	/AGN	S 101867331/AGN	AGN
Application Country (WIPO code and text)	/AC	S CN/AC	AI
Application Date **(1)**	/AD	S AD=JAN 2008	AI
Application Kind Code	/AK	S CNA/AK	AI
Application Number **(2)**	/AP	S CN 2011-10135271/AP	AI
Application Number Original	/APO	S CN00100009/APO	APO
Application Year **(1)**	/AY	S AY>=2000	AI
Claims*	/CLM	S DERIVATION/CLM	CLM
Claims (English)	/CLMEN	S DERIVATION/CLMEN	CLM, CLMEN
Claims, Claim Groups *	/CLM.CG	S OFFICE CHAIR/CLM.CG	CLM.CG, CLM
Claims, Independent Claims *	/CLM.IC	S OFFICE CHAIR/CLM.IC	CLM.IC, CLM
Cooperative Patent Classification **(3)**	/CPC	S C12N0009/CPC	CPC
Cooperative Patent Classification, Action Date	/CPC.ACD	S 20121113/CPC.ACD	CPC.TAB
Cooperative Patent Classification, Keyword	/CPC.KW	S C12N0009/CPC (S) I/CPC.KW	CPC.TAB
Cooperative Patent Classification, Version	/CPC.VER	S 20130101/CPC.VER	CPC.TAB
Data Entry Date (1)	/DED	S 20221013/DED	DED
Data Update Date (1)	/DUPD	S 20221013/DUPD	DUPD
Detailed Description	/DETD	S LASER LIGHT/DETD	DETD
Detailed Description (English)	/DETDEN	S LASER LIGHT/DETDEN	DETD, DETDEN
Entry Date of Fulltext **(1)**	/EDTX	S 20120324/EDTX	EDTX
European Patent Classification **(3)**	/EPC (or /ECLA)	S A01B0001-02H/EPC	EPC
Field Availability	/FA	S AB/FA	FA
International Patent Classification (ICM, ICS, IPCI, IPCR) **(3)**	/IPC	S A01B001/IPC	ICM, ICS, IPCI, IPCR
International Patent Classification IPC (ICM, ICS, ICA, ICI)	/IC (or IPCMS)	S A45D/IC	IC, ICM, ICS, ICA, ICI
ICO (in-computer-only) Classification **(3)**	/ICO	S L29C0045-00/ICO	ICO
Inventor	/IN (or /AU)	S ZHANG TING /IN S ZHANG?/IN	IN
Inventor, Country (WIPO code and text)	/IN.CNY	S CN/IN.CNY	IN, IN.CNY
IPC, Action Date **(1)**	/IPC.ACD	S 13 JAN 2006/IPC.ACD	IPC.TAB
IPC, Initial	/IPCI	S B21B0001/IPCI	IPCI, IPC
IPC, Keyword Terms	/IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Main	/ICM (or IPCM)	S A62B037-00/ICM	ICM, IC
IPC, Reclassified	/IPCR	S B21C0037-20/IPCR	IPCR, IPC
IPC, Reform	/IPC.REF	S A01B0001-04/IPC.REF	IPC.TAB
Key Terms*	/KT	S PROTEIN SYNTHESIS/KT S “BIOAVAILABLE PROTEIN AND STARCH”/KT	KT

General Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Locarno Classification	/LCL	S 19-02/LCL	LCL
Main Claim*	/MCLM	S ?FRACTURE?/MCLM	MCLM
Main Claim in English	/MCLMEN	S ALLOPURINOL/MCLMEN	MCLMEN
Number of Claims **(1)**	/CLMN	S 5-7/CLMN	CLMN
Number of Paragraphs in DETD (Detailed Description) **(1)**	/DETN	S DETN<10	DETN
Patent Assignee **(4)**	/PA (or /CS)	S HUAWEI TERMINAL CO LTD /PA	PA
Patent Assignee, Country	/PA.CNY	S CN/PA.CNY	PA, PA.CNY
Patent Assignee, Total	/PA.T	S CN/PA.CNYS HUAWEI TERMINAL CO LTD/PA	PA
Patent Assignee Normalized **(4)**	/PAN	S HUAWEI/PAN	PAN
Patent Assignee Standardized **(4)**	/PAS	S HUAWEI TECH/PAS	PAS
Patent Country (WIPO code and text)	/PC	S CN/PC	PI
Patent Information Publication Type	/PIT	S CNA UNEXAMINED APPLICATION FOR A PATENT FOR INV./PIT	PIT
Patent Kind Code	/PK	S CNA/PK	PI
Patent Number **(2)**	/PN	S CN 102326444/PN	PI
Patent Number, Original	/PNO	S CN100358571/PNO	PNO
Patent Number/Kind Code	/PNK	S CN102326444 A/PNK	PI
Physical Properties	/PHP	S VOLT/PHP (S) TOUCH SCREEN/BI	KWIC
Priority Country (WIPO code and text)	/PRC	S CN/PRC or S CHINA/PRC	PRN
Priority Date **(1)**	/PRD	S PRD=MAY 20, 2003 S 20030520/PRD	PRN
Priority Date, First **(1)**	/PRDF	S 20010614/PRDF	PRN
Priority Number **(2)**	/PRN	S DE2004-102004063820/PRN	PRN
Priority Number, Original	/PRNO	S US10001608P/PRNO	PRNO, PRAO
Priority Year **(1)**	/PRY	S 2003/PRY	PRN
Priority Year, First **(1)**	/PRYF	S 2003-2004/PRYF	PRN
Publication Date **(1)**	/PD	S PD=JAN-FEB 2008	PI
Publication Year **(1)**	/PY	S PY>2008 AND L1	PI
Related Application Country	/RLC	S WO/RLC	RLI
Related Application Number	/RLN	S WO2005-CN1971/RLN	RLI
Related Application Date **(1)**	/RLD	S 20050329/RLD	RLI
Related Application Type	/RLT	S PARENT APPLICATION/RLT	RLI
Related Application Year **(1)**	/RLY	S 2005/RLY	RLI
Related Patent Country	/RLPC	S WO/RLPC	RLI
Related Patent Date **(1)**	/RLPD	S 20230420/RLPY	RLI
Related Patent Number	/RLPN	S WO2000000038/RLPN	RLI
Related Patent Year **(1)**	/RLPY	S 2023/RLPY	RLI
Title*	/TI	S FLUID###/TI	TI
Title (English)	/TIEN	S FLUID###/TIEN	TI, TIEN
Ultimate Owner **(4)**	/UO	S BASF/UO	UO
Ultimate Owner Standardized **(4)**	/UOS	S BASF/UOS	UOS
Update Date **(1)**	/UP	S UP=APRIL 2012	UP
Update Date, Full Text **(1)**	/UPTX	S 20230910/UPTX	UPTX

(1) Numeric search field that may be searched using numeric operators or ranges.
(2) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
(3) An online thesaurus is available in this field.
(4) Search with implied (S) proximity is available in this field.

Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group	/APPS	AP, PRN, RLN	S WO 2021-CN124037 /APPS	AI, PRAI, APPS
Patent Assignee Group	/PASS	PA, PA.T, PAS, PAN, UO, UOS	S BASF/PASS	PA, PAN, PAS, UO, UOS
Patent Number Group	/PATS	PN, RLPN	S CN216083304U/PATS	PI, RLI

Property Fields [(1)]

In CNFULL a numeric search for a specific set of physical properties (/PHP) is available within the full-text fields (TI, AB, DETD and CLM). The numeric values are not displayed as single fields but are instead highlighted within the hit displays.

Use EXPAND A/PHP to search for all available physical properties. A search with the respective field codes will be carried out in all database fields with English text. The /PHP index contains a complete list of codes and related text for all physical properties available for numeric search.

Field Code	Property	Unit	Symbol	Search Examples
/AOS	Amount of Substance	Mol	mol	S 10 /AOS
/BIR	Bit Rate	Bit/Second	bit/s	S 8000-10000/BIR
/BIT	Stored Information	Bit	Bit	S BIT > 3 MEGABIT
/CAP	Capacitance	Farad	F	S 1-10 MF/CAP
/CATA	Catalytic Activity	Katal	kat	S 1-10/CATA
/CDN	Current Density	Ampere/Square Meter	A/m^2	S CDN>10 A/M**2
/CMOL	Molarity, Molar Concentration	Mol/Liter	mol/L	S UREA/BI (S) 8/CMOL
/CON	Conductance	Siemens	S	S 1S-3/CON
/DB	Decibel	Decibel	dB	S DB>50
/DEG	Degree	Degree	°	S CYLINDER/BI (S) 45/DEG
/DEN (/C)	Density (Mass Concentration	Kilogram/Cubic Meter	kg/m^3	S 5E-3-10E-3/DEN
/DEQ	Dose Equivalent	Sievert	Sv	S 100/DEQ
/DOA	Dosage	Milligram/Kilogram/Day	mg/kg/day	S 100-300/DOA
/DOS (/LD50)	Dose	Milligram/Kilogram	mg/kg	S DOS>0.8
/DV	Viscosity, dynamic	Pascal * Second	Pa*s	S DV>5000
/ECH (/CHA)	Electric Charge	Coulomb	C	S 0.0001-0.001/ECH
/ECO (/ECND)	Electrical Conductivity	Siemens/Meter	S/m	S ECO>800 S/M (15A) AQUEOUS
/ELC (/ECC)	Electric Current	Ampere	A	S 1-10/ELC
/ELF (/ECF)	Electric Field	Volt/Meter	V/m	S 200/ELF
/ENE	Energy	Joule	J	S DROPLETS (10A) 40 JOULE - 70 JOULE /ENE
/ERE (/ERES)	Electrical Resistivity	Ohm*Meter	Ohm*m	S ERE>0.1
/FOR	Force	Newton	N	S 50 N /FOR
/FRE (/F)	Frequency	Hertz	Hz	S OSCILLAT?/BI (S) 1- 3/FRE
/IU	International Unit	none	IU	S IU>1000 (P) VITAMIN A
/KV	Viscosity, kinematic	Square Meter/Second	M^2/s	S METHYLPOLYSILOXANES/BI (10A) 200-300 CST /KV
/LEN (/SIZ)	Length, Size	Meter	m	S 1-4/LEN
/LUME	Luminous Emittance, Illuminance	Lux	lx	S 10-50/LUME
/LUMF	Luminous Flux	Lumen	Lm	S LUMF>1000
/LUMI	Luminous Intensity	Candela	cd	S LUMI<4
/M	Mass	Kilogram	kg	S ALLOY/BI (30A) 1E-10-1E-5/M
/MCH	Mass to Charge Ratio	none	m/z	S MCH=1
/MFD (/MFS)	Magnetic Flux Density	Tesla	T	S MFD>102
/MFR (/MFL)	Mass Flow Rate	Kilogram/Second	kg/s	S MFR<0.1
/MFST	Magnetic Field Strength	Ampere/Meter	A/m	S 45-50/MFST
/MM (/MW, /MOM)	Molar Mass	Gram/Mol	g/mol	S 2000-3000 G/MOL/MM
/MOLS	Molality of Substance	Mol/Kilogram	mol/kg	S 01.-10 MOL/KG/MOLS

Property Fields (cont'd)

Field Code	Property	Unit	Symbol	Search Examples
/MVR	Melt Volume Rate, Melt Flow Rate	none	g/10 min	S 3/MVR
/PER	Percent (Proportionality)	none	%	S POLYMER?/AB (5A) 4/PER
/PHV (/PH)	pH Value	pH	pH	S 7.4-7.6/PHV
/POW (/PW)	Power	Watt	W	S "HG-XE-?"/BI (S) 100-200 WATT/POW
/PPM	Parts per million	Ppm	ppm	S 100 PPM /PPM (10A) ADDITIVE/BI
/PRES (/P)	Pressure	Pascal	Pa	S (VACUUM (5A) DISTILL?)/BI (S) 1000-1100/PRES
/RAD	Radioactivity	Becquerel	Bq	S 1-10/RAD
/RES	Electrical Resistance	Ohm	Ohm	S SENSOR /BI (S) 10- 100/RES
/RI	Refractive Index	none		S 3-4/RI
/RSP	Rotational Speed	Revolution/Minute	rpm	S 2 RPM - 100 RPM /RSP (S) ENGINE/BI
/SAR	Area /Surface Area	Square Meter	m^2	S PLATE/BI (S) 10 M**2 - 100 M**2 /SAR
/SOL (/SLB)	Solubility	Gram/100 gram	g/100g	S SOL>20 G/100G (5A) WATER
/SSAM	Specific Surface Area, Mass	Square Meter/ Kilogram	m^2/kg	S 1-10/SSAM
/STSC (/ST)	Surface Tension	Joule /Square Meter	J/m^2	S 60 J/M**2/STSC
/TCO (/TCND)	Thermal Conductivity	Watt/Meter*Kelvin	W/m*K	S 1/TCO (S) HEAT?
/TEMP (/T)	Temperature	Kelvin	K	S 20-25/TEMP
/TEX	Tex	Gram/Kilometer	g/km	S 1-5/TEX
/TIM	Time	Second	s	S ?INCUB?/BI (10A) 50 S - 150 S /TIM
/VEL (/V)	Velocity	Meter per Second	m/s	S REDUC?/BI (S) 1E-3-5E-3/VEL
/VELA	Velocity, angular	Radian/Second	rad/s	S VELA>10
/VLR	Volumetric Flow Rate	Cubic Meter/Second	m^3/s	S 1 M**3/S - 2 M**3/S /VLR (S) ABRASIVE
/VOL	Volume	Cubic Meter	m^3	S 1E-8-2E-8/VOL.EX
/VOLT	Voltage	Volt	V	S TENSION/BI (10A) 5E-3 V <VOLT<7E-3 V

(1) Exponential format is recommended for the search of particularly high or low values, e.g., 1.8E+7 or 1.8E7 (for 18000000) or 9.2E-8 (for 0.000000092).

International Patent Classification (/IPC) Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1–7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Code	Content	Examples
ADVANCED (ADV)	Advanced Codes for the Core Level IPC Code	E A61K0006-02+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (BT, SELF)	E C01F001-00+BT/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual edition	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader, Narrower Term) (BT, SELF, NT)	E C01B003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
PREV	Previous Classification	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

ECLA (/EPC) Thesaurus

This thesaurus is available in the /EPC search field (for ECLA codes). All relationship codes can be used with both the EXPAND and SEARCH commands. Note that the CPC replaced the EPC in 2013.

Code	Content	Search Examples
ALL	All usually required terms (BT, SELF, CODE, DEF)	E C12M0001-34H2+ALL/EPC
AUTO **(1)**	Automatic relationship (BT, SELF, CODE, DEF)	E G01J003-443+AUTO/EPC
BT	Broader terms (BT, SELF)	E G01J0003-443+BT/EPC
CODE	Classification Code (SELF, CODE)	E MOVING SCRAPER+CODE/EPC
DEF	Definition (SELF, DEF)	E B65G0045-16+DEF/EPC
HIE	Hierarchy terms (broader and narrower terms) (BT, SELF, DEF, NT)	E A01B0001+HIE/EPC
KT	Keyword terms (SELF, KT)	E LASER+KT/EPC
MAX	All associated terms	E G01J0003-44B+MAX/EPC
NEXT	Next classification within the same class (SELF, NEXT)	E A01B0001-24+NEXT/EPC
NEXT(n)	Next n classification within the same class	E A01B0001-24+NEXT3/EPC
NT	Narrower terms	E G05B0001-04+NT/EPC
PREV	Previous Code within the same class (SELF, PREV)	E G05B0019-418N1+PREV/EPC
PREV(n)	Previous n classifications within the same class	E G05B0019-418N1+PREV2/EPC
TI	Complete Title of SELF Term and Broader Terms (BT, SELF)	E G05B0001-03+TI/EPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

CPC Thesaurus

This thesaurus is available in the /CPC search field. All relationship codes can be used with both the EXPAND and SEARCH commands.

Code	Content	Search Examples
ALL	All usually required terms (BT, SELF, CODE, DEF)	E C12M0001-005+ALL/CPC
AUTO **(1)**	Automatic relationship (BT, SELF, CODE, DEF)	E G01J003-443+AUTO/CPC
BT	Broader terms (BT, SELF)	E G01J0003-443+BT/CPC
CODE	Classification Code (SELF, CODE)	E CARTRIDGES+CODE/CPC
DEF	Definition (SELF, DEF)	E B65G0045-16+DEF/CPC
HIE	Hierarchy terms (broader and narrower terms) (BT, SELF, DEF, NT)	E A01B0001+HIE/CPC
KT	Keyword terms (SELF, KT)	E LASER+KT/CPC
MAX	All associated terms	E G01J0003-44+MAX/CPC
NEXT	Next classification within the same class (SELF, NEXT)	E A01B0001-24+NEXT/CPC
NEXT(n)	Next n classification within the same class	E A01B0001-24+NEXT3/CPC
NT	Narrower terms	E G05B0001-04+NT/CPC
PREV	Previous Code within the same class (SELF, PREV)	E G05B0019-00+PREV/CPC
PREV(n)	Previous n classifications within the same class	E G05B0019-00+PREV2/CPC
TI	Complete Title of SELF Term and Broader Terms (BT, SELF)	E G05B0001-03+TI/CPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PA. The fields are displayed or printed in the order requested.

The information of the latest publication is displayed by default. To display the content for all levels of the record you can combine all display fields and formats with the qualifier .M except FA, SCAN, and TRIAL. The default display format is STD.M, i.e., all publication levels of one family in the STD format.

For displaying a particular publication of a database record, you can simply add for certain display field the kind code to the appropriate display format, e.g., ALL.A. Fields that allow this are indicated by a number (3).

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB (ABS)	Abstract	D TI AB 1-5
ABEN	Abstract (English)	D ABEN
ABZH	Abstract (Chinese)	D ABZH
AGZH	Agent (Chinese)	D AGZH
AI (AP) **(1)**	Application Information	D AI
AN	Accession Number	D L3 AN
APO	Application Number Original	D APO
CLM **(3)**	Claims	D CLM
CLM.CG **(3)**	Claims, Claim Group	D CLM.CG
CLM.IC **(3)**	Claims, Independent Claims	D CLM.IC
CLMEN **(3)**	Claims (English)	D CLMEN
CLMN **(2)**	Number of Claims	D CLMN
CPC	Cooperative Patent Classification	D CPC
CPC.TAB	CPC, Tabular	D CPC.TAB
DED	Data Entry Date	D DED
DETD **(3)**	Detailed Description	D DETD
DETDEN **(3)**	Detailed Description (English)	D DETDEN
DETN **(2)**	Number of Paragraphs in DETD	D DETN
DT (TC)	Document Type	D DT
DUPD	Data Update Date	D DUPD
ED	Entry Date	D ED
EDTX	Entry Date of Full-text	D EDTX
EPC	European Patent Classification	D EPC
FA	Field Availability (for all publication levels)	D FA
GI	Graphic Image	D GI
IC	IPC (format contains ICM, ICS)	D IC
ICM	IPC, Main	D IC
ICO	ICO (in-computer-only) Classification	D ICO
ICS	IPC, Secondary	D ICS
IN (AU)	Inventor	D IN
IN.CNY	Inventor, Country	D IN.CNY
INZH	Inventor (Chinese)	D INZH
IPC	IPC, version 1-8 (format contains ICM, ICS, ICA, ICI, IPCI, IPCR)	D IPC
IPC.TAB	IPC, Tabular Format	D IPC.TAB
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	D LA
LAF	Language of Filing	D LAF
LCL	Locarno Classification	D LCL
MCLM	Main Claim	D MCLM
PA (CS)	Patent Assignee	D PA
PA.CNY	Patent Assignee, Country	D PA.CNY
PAN	Patent Assignee Normalized	D PAN
PAS	Patent Assignee Standardized	D PAS
PAZH	Patent Assignee (Chinese)	D PAZH
PI (PN, PATS) **(1)**	Patent Information	D PI
PIT	Patent Information Publication Type	D PIT
PNO	Patent Number, Original Format	D PNO
PRN (PRAI) (1,5)	Priority Information	D PRN

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
PRNO (PRAO) **(2)**	Priority Number, Original Format	D PRNO
PRYF	Priority Year, First	D PRYF
RLI (RLN)	Related Application Number	D RLI
RLPI	Related Patent Information	D RLPI
TI	Title	D TI
TIEN	Title (English)	D TIEN
TIZH	Title (Chinese)	D TIZH
UO	Ultimate Owner	D UO
UOS	Ultimate Owner Standardized	D UOS
UP	Update Date	D UP
UPTX	Update Date (English)	D UPTX
ALL **(1,3)**	AN, ED, EDP, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, PA, PAS, PAN, UO, UOS, AGN, LAF, LA, DT, PI, PIT, AI, PRAI, RLPI, RLI, IPC, CPC, EPC, ICO, LCL, ABEN, DETDEN, CLMEN, KT	D ALL
IALL **(1,3)**	ALL, indented with text labels	D IALL
DALL **(1)**	ALL, delimited for post processing	D DALL
ALLG **(1)**	ALL, plus graphic image	D ALLG
IALLG **(1)**	IALL plus graphic image	D IALLG
ALLO **(1,3)**	AN, EDP, ED, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, INZH, PA, PAZH, PAS, PAN, UO, UOS, AGZH, AGN, LAF, LA, DT, PI or PNO (if no PI), PIT, AI or APO (if no AI), PRAI or PRAO (if no PRAI), RLPI, RLI, IPC, CPC, EPC, ICO, LCL, ABEN, ABZH, DETDEN, CLMEN, KT	D ALLO
APPS **(1)**	AI, RLN, PRAI	D APPS
BIB **(1)**	AN, ED, EDP, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, PA, PAS, PAN, UO, UOS, AGN, LAF, LA, DT, PI, PIT, AI, PRAI, RLI	D BIB
IBIB **(1)**	BIB, indented with text labels	D IBIB
BIBG **(1)**	BIB, plus graphic image	D BIBG
IBIBG **(1)**	IBIB, plus graphic image	D IBIBG
BIBO **(1)**	AN, EDP, ED, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, INZH, PA, PAZH, PA.NO, PAS, PAN, UO, UOS, AGN, AGZH, LAF, LA, DT, PI or PNO (if no PI), PIT, AI or APO (if no AI), PRAI or PRAO (if no PRAI), RLPI, RLI	D BIBO
BRIEF **(1)**	AN, EDP, ED, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, PA, PAS, PAN, UO, UOS, AGN, LAF, LA, DT, PI, PIT, AI, PRAI, RLPI, RLI, IPC, CPC, EPC, ICO, LCL, ABEN, MCLM, KT	D BRIEF
IBRIEF **(1)**	BRIEF, indented with text labels	D IBRIEF
BRIEFG **(**1,**4)**	BRIEF, plus graphic image	D BRIEFG
IBRIEFG **(1,4)**	BRIEFG, indented with text labels	D IBRIEFG
BRIEFO **(1)**	AN, EDP, ED, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, INZH, PA, PAZH, PAS, PAN, UO, UOS, AGZH, AGN, LAF, LA, DT, PI, PIT, AI, PRAI, RLPI, RLI, IPC, CPC, EPC, ICO, LCL, ABEN, ABZH, MCLM, KT	D BRIEFO
IND	IPC (ICM, ICS, IPCI, IPCR), CPC, EPC, ICO, LCL	D IND
MAX (ALL.M) **(1)**	AN, EDP, ED, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, INZH, PA, PAS, PAN, UO, UOS, PAZH, AGN, AGZH, LAF, LA, DT, PI, PIT, AI, PRAI, RLPI, RLI, IPC, CPC, EPC, ICO, LCL, ABEN, DETDEN, CLMEN, FA, KT for all levels of publication	D MAX
IMAX (IALL.M) **(1)**	MAX, indented with text labels	D IMAX
MAXG (ALLG.M) **(1)**	MAX, plus graphic image	D MAXG
IMAXG (IALLG.M) **(1)**	IMAX, plus graphic image	D IMAXG
SCAN **(4)**	TI (random display without answer numbers)	D SCAN
STD (STD.M) **(1,6)**	AN, EDP, ED, EDTX, UP, UPTX, DED, DUPD, TIEN, TIZH, IN, PA, PAS, PAN, UO, UOS, AGN, LAF, LA, DT, PI, PIT, AI, PRAI, RLPI, RLI, IPC, CPC, EPC, ICO, LCL	D STD
ISTD **(1)**	STD, indented with text labels	D ISTD
STDG **(1)**	STD, plus graphic image	D STDG
ISTDG **(1)**	ISTD, plus graphic image	D ISTDG
TRIAL (TRI, SAM, SAMPLE, FREE)	EDP, ED, EDTX, UP, UPTX, DED, DUPD, TIEN, FA, DETN, CLMN	D TRIAL
TX	DETDEN, CLMEN	D TX

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
HIT	Hit term(s) and field(s)	D HIT
KWIC	Up to 50 words before and after hit term(s) (KeyWord-In-Context)	D KWIC
OCC	Number of occurrences of hit term(s) and field(s) in which they occur	D OCC

(1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
(2) Custom display only.
(3) You can combine this display field with the qualifier .PK (Patent Kind Code) to display the content for a certain publication level of a record, e.g., CLM.B2.
(4) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.
(5) If priority information is not available for a certain document, this information is taken from the application information of this document and marked with an asterisk (*).
(6) The default display format is STD.M, i.e., all publication levels of one family in the STD format.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

You can combine all fields except FA with the qualifier .M to SELECT/ANALYZE the content of all publication levels.

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y	Y
Abstract (English)	ABEN	Y	Y
Accession Number	AN	Y	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Information	AI (AP)	Y **(2)**	Y
Application Kind Code	AK	Y	Y
Application Number Group	APPS	Y	Y
Application Number Original	APO	Y	Y
Application Year	AY	Y	Y
Cooperative Patent Classification	CPC	Y	Y
Data Entry Date	DED	Y	Y
Data Update Date	DUPD	Y	Y
Document Type	DT (TC)	Y	Y
Entry Date	ED	Y	Y
Entry Date Full Text	EDTX	Y	Y
European Patent Classification	EPC (ECLA, EPCLA)	Y	Y
Field Availability	FA	Y	N
International Patent Classification	IC	Y	Y
ICO (in-computer-only) classification	ICO	Y	Y
Inventor	IN (AU)	Y	Y
Inventor, Country	IN.CNY	Y	Y
IPC (ICM, ICS, IPCI, IPCR)	IPC	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y **(3)**	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y **(3)**	N
IPC, Core Level	IPC.C	Y	N
IPC, Core Level for Invention	IPC.CI	Y	N
IPC, Initial	IPCI	Y	Y
IPC, Main	ICM (IPCM)	Y	Y
IPC, Reclassified	IPCR	Y	Y
IPC, Reform	IPC.REF	Y	N
IPC, Secondary	ICS (IPCS)	Y	Y
Key Terms	KT	Y	N
Language	LA	Y	Y
Language of Filing	LAF	Y	Y
Locarno Classification	LCL	Y	Y
Number of Claims	CLMN	Y	Y
Number of Paragraphs in DETD	DETN	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee	PA (CS)	Y	Y
Patent Assignee, Country	PA.CNY	Y	Y
Patent Assignee, Total	PA.T	Y	N
Patent Assignee Normalized	PAN	Y	Y
Patent Assignee Standardized	PAS	Y	Y
Patent Country	PC	Y	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Patent Number	PN (PI)	Y (default)	Y
Patent Number, Original	PNO	Y	Y
Patent Number Group	PATS	Y	Y
Patent Number/Kind Code	PNK	Y	Y
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006-present (IPC, Main or First)	IPC.F	Y **(3)**	Y
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Date, First	PRDF	Y	Y
Priority Number	PRN (PRAI)	Y	Y
Priority Number, Original	PRNO	Y	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Related Patent Country	RLC	Y	Y
Related Application Number	RLN	Y	Y
Related Application Date	RLD	Y	Y
Related Application Type	RLT	Y	Y
Related Application Year	RLY	Y	Y
Related Patent Country	RLPC	Y	Y
Related Patent Date	RLPD	Y	Y
Related Patent Number	RLPN	Y	Y
Related Patent Year	RLPY	Y	Y
Title	TI	Y	Y
Title (English)	TIEN	Y	Y
Ultimate Owner Normalized	UO	Y	Y
Ultimate Owner Standardized	UOS	Y	Y
Update Date	UP	Y	Y
Update Date Full Text	UPTX	Y	Y

(1) HIT may be used to restrict terms extracted to terms that match search expression used to create the answer set, e.g., SEL HIT TI.
(2) Selects or analyzes application numbers with /AP appended to the terms created by SELECT.
(3) Appends /IPC to the terms created by SELECT.

Sample Records

DISPLAY MAX

AN 35755134 CNFULL EDP 20201116 ED 20201116 UP 20240505 EDTX 20201116 UPTX 20210303
DED 20201103 DUPD 20240430 Full-text
TIEN ACK/NACK information feedback method of downlink data and related equipment
TIZH 下行数据的ACK/NACK信息反馈方法及相关设备
IN XUE YIFAN; LIU YUN; WANG DA; WANG JIAN; ZENG YONGBO
PA HUAWEI TECH CO LTD;
PAS HUAWEI TECH
PAN HUAWEI
UO SHENZHEN HUAWEI INVESTMENT AND HOLDING CO., LTD.
UOS Huawei
LAF English
LA Chinese
DT Patent; (Fulltext)
PI CN 111884772 A 20201103
PIT CNA UNEXAMINED APPLICATION FOR A PATENT FOR INV.
AI CN 2020-10547519 20161010
PRAI WO 2016-CN100503 20160928
CN 2016-80089669 20161010
RLI WO 2016-CN100503 20160928 PCT Application
IPCI H04L0001-18 [I,A]; H04L0005-00 [I,A]; H04W0072-04 [I,A]; H04W0074-08 [I,A]
CPC H04L0001-1864; H04L0001-1896; H04L0005-0064; H04L0001-1812; H04L0001-1825; H04L0005-0055; H04L0001-1893; H04W0074-0833; H04W0072-23

AB

Original
[DESC0001] The embodiment of the invention discloses an ACK/NACK information feedback method for downlink data, and the method comprises the following steps: acquiring processing capacity information of user equipment, and reporting the processing capacity information to a base station; acquiring data information of the downlink data packet; according to the processing capability information and the data information, calculating basic delay time required by the user equipment for performing data decoding and ACK/NACK information coding on the downlink data packet; receiving extra delay time issued by the base station for the downlink data packet, wherein the extra delay time is used for indicating the position of a subframe for feeding back ACK/NACK information corresponding to the downlink data packet; and selecting a corresponding subframe to feed back ACK/NACK information corresponding to the downlink data packet according to the sum of the basic delay time and the additional delay time. In addition, the embodiment of the invention also discloses a base station and user equipment using the method. The method can effectively reduce data transmission delay.

DETDEN

[DESC0001] Technical Field

[DESC0002] The invention relates to the technical field of communication, in particular to an ACK / NACK information feedback method of downlink data and related equipment.

[DESC0003] Background Art

[DESC0004] With the new generation 5G communication technology entering the discussion phase, it is necessary to consider whether the system structure and the access procedure that have been achieved in the existing 4G Long Term (LTE) communication technology continue to be adopted. On the one hand, since the communication system is a late compatible technique, new technologies developed later tend to be compatible with prior art techniques; on the other hand, since 4G LTE has already existed a large number of existing designs, much flexibility of 5G must be sacrificed to reduce performance in order to achieve

compatibility. , In 3 GPP tissues, the backward compatibility and the backward compatibility are studied in parallel from the consideration of backward compatibility. In both directions, the backward compatible technical direction is not considered, and is referred to as 5G new air interface (New Radio, NR).

...

[DESC0415] It is to be understood by those skilled in the art that all or part of the flow of the foregoing embodiments may be practiced without departing from the scope of the invention as defined by the appended claims.

CLMEN

[CLM0001] 1.A transmission method of ACK / NACK information of data is characterized by comprising the following steps:
Transmitting data packets to a user device.
Control signaling is used for indicating first time delay of determining ACK / NACK information corresponding to the data packet by the user equipment. The second Time delay corresponding to the processing capability of the user equipment is determined. ACK / NACK information corresponding to the data packet transmitted by the user equipment is received based on the first latency and the second latency.

[CLM0002] 2.The method according to claim 1, wherein the ACK / NACK information corresponding to the data packet transmitted by the user equipment is received based on the first latency and second latency. Based on the first latency and the second latency, a subframe used by the user equipment to transmit ACK / NACK information corresponding to the data packet is determined. ACK / NACK information corresponding to the data packet is received on a subframe used for transmitting ACK / NACK information corresponding to the data packet by the user equipment.

...

[CLM0022] 22.A user equipment comprising at least one processor, a memory, a communication interface and a bus, wherein the at least one processor, the memory and the communication interface communicate with each other through the bus; the communication interface is configured to establish a communication connection with a base station; and the processor is configured to call executable program code stored in the memory and execute the method of claim 10-20.

KT

downlink data; feedback method; data packet; subframe time; user equipment; balance signaling load; transmission time; delay receiving; base delay calculating; n-th subframe; uplink data; delay acquisition subunit; communication delay; downlink subframe; traffic delay requirement; user device; added field; rrc establishment; reconstruction instruction; base delay amount; base station; sequence packet subunit; random access access response; random access procedure; communication interface; time delay; delay issue subunit; radio resource control rrc; uplink timing advance; time division duplex

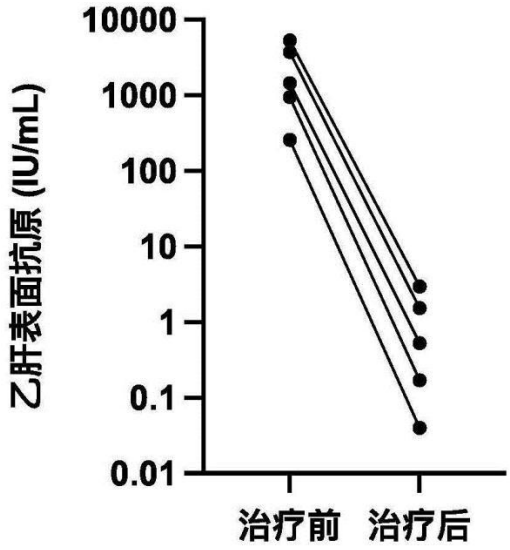
DISPLAY BRIEFG

AN 43233725 CNFULL EDP 20230122 ED 20230122 UP 20230723 EDTX 20230122 DED 20230118 DUPD 20230718 Full-text
TIEN Preparation method of mesenchymal stem cells for preventing hepatitis B virus from infecting hepatocytes
TIZH 一种阻断乙肝病毒感染肝细胞的间充质干细胞的制备方法
IN MA YIDONG; WANG MIAOMIAO; LI WEIGUO
PA SHANGHAI JUNYIHE BIOMEDICAL TECH CO LTD;
PAS SHANGHAI JUNYIHE BIOMEDICAL TECH
UO SHANGHAI JUNYIHE BIOMEDICAL TECH
UOS SHANGHAI JUNYIHE BIOMEDICAL TECH
AGN 36129
DT Patent; (Fulltext)

CNFULL

PI CN 115612672 A 20230117
PIT CNA UNEXAMINED APPLICATION FOR A PATENT FOR INV.
AI CN 2022-11345911 20221031
PRAI CN 2022-11345911 20221031
IPCI C12N0005-10 [I,A]; A61K0038-16 [I,A]; A61K0048-00 [I,A]; A61P0031-20 [I,A]; C12N0015-11 [I,A]; C12N0015-867 [I,A]
CPC C07K0014-00; C12N2740-15043; C12N2510-00; C12N0005-0668; A61K0048-005; A61P0031-20; A61K0048-0008; C12N0015-86; A61K0038-162; C12N2509-10; C12N2509-00

GI



AB

Original
The invention discloses a preparation method of mesenchymal stem cells for treating chronic hepatitis B, and relates to the field of cell therapy. Specifically, the invention relates to construction of mesenchymal stem cells for expressing Heiprala peptide, and the construction method comprises the following steps: Step 1, isolated culture of umbilical cord mesenchymal stem cells; step2, construction of a gene vector of PreS1.47, and construction of a gene vector of PreS1.47; 3, a lentiviral vector carrying the PreS1.47 gene is prepared, and a lentiviral vector carrying the PreS1.47 gene is prepared; step 4, carrying out gene modification on the mesenchymal stem cells; carrying out PreS 1.47 to MSC (mesenchymal stem cell) amplification; and Step 5. PreS1.47-MSC is used for treating the chronic hepatitis B. According to the invention, mesenchymal stem cells are used as a drug carrier to express the Heiprala peptide, repeated infection of hepatitis B virus is blocked by means of intravenous infusion administration, chronic hepatitis B is treated, and the Heiprala peptide has more targeting effect and lasting action effect in vivo on treatment of hepatitis B by means of the characteristic that the liver is an organ where the mesenchymal stem cells are mainly accumulated.

MCLMEN

[CLM0001] 1. A method for preparing mesenchymal stem cells that block hepatitis B virus infected hepatocytes, characterized in that it includes the following steps:
Step1. Isolation and culture of umbilical cord mesenchymal stem cells;
Step2.Construction of PreS1.47 gene vector;
Step3.Preparation of lentiviral vectors carrying PreS1.47 gene;
Step4. Gene modification of mesenchymal stem cells;
Step5.PreS1.47-MSC amplification;
Step5.PreS1.47-MSC for chronic hepatitis B.

KT

mesenchymal stem cell; cell culture dish; umbilical cord tissue; umbilical cord protection solution; heiprala peptide; cell culture incubator; tissue block; mscbm complete medium culture; cell confluency;

sterile petri dish; cell therapy; seed cell; centrifuged cell; cell density; cell passage; liver cell; cell number; cell suspension; cell debris; residual disinfectant alcohol; saline working solution; chronic hepatitis; construction method; lentiviral packaged helper plasmid; sterilized pbs solution; tissue forcep; chronic inflammatory site; chronic hbv infection; glial tissue; lmscbm complete medium

DISPLAY BIB.M

AN 44082026 CNFULL EDP 20210607 ED 20210607 UP 20240129 EDTX 20210607 UPTX 20210930
DED 20210601 DUPD 20240123 Full-text
TIEN Electric torque wrench
TIZH 一种电动扭矩扳手
IN CHEN LIANGLIANG
PA SHANGHAI LUOMA POWER TECH CO LTD;
PAS SHANGHAI LUOMA POWER TECH
UO SHANGHAI LUOMA POWER TECH
UOS SHANGHAI LUOMA POWER TECH
AGN 11777
LAF English
LA Chinese
DT Patent; (Fulltext)
PI CN 112873111 A 20210601
PIT CNA UNEXAMINED APPLICATION FOR A PATENT FOR INV.
AI CN 2020-11545592 20201224
PRAI CN 2020-11545592 20201224

AN 44082026 CNFULL EDP 20210607 ED 20230709 UP 20230730 EDTX 20230709
DED 20230704 DUPD 20230726 Full-text
TIEN An electric torque wrench
TIZH 一种电动扭矩扳手
PA SHANGHAI LUOMA POWER TECH CO LTD;
PAS SHANGHAI LUOMA POWER TECH
UO SHANGHAI LUOMA POWER TECH
UOS SHANGHAI LUOMA POWER TECH
AGN 34126; 34126
LAF English
LA Chinese
DT Patent; (Fulltext)
PI CN 112873111 B 20230704
PIT CNB EXAMINED APPLICATION [FROM 19850401 UNTIL 19921231] or GRANTED PATENT FOR INVENTION [FROM 20100407 ONWARDS]
AI CN 2020-11545592 20201224
PRAI CN 2020-11545592 20201224